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# TABLE OF CONTENTS

## A: CALIBRATIONS METHODS & TECHNIQUES

Correction for Line Length Errors and Center-Conductor-Gap Variation in the Coaxial Multiline Through-Reflect-Line Calibration .....	1
<i>A. Lewandowski, W. Wiatr</i>	
Common Adapter/fixture Extraction Techniques: Sensitivities to Calibration Anomalies.....	8
<i>J. Martens</i>	
S-parameters of Slotted and Slotless Coaxial Connectors.....	18
<i>Johannes Paul Hoffmann, Pascal Leuchtmann, Juerg Ruefenacht, Ken Wong</i>	
Design and Measurement of a WR-42 Calorimeter .....	23
<i>Xiaohai Cui, Xinneng Liu, Yong Li, Jingyuan Miao, Hui Xu</i>	

## B: RF MEASUREMENT METHODS & APPLICATIONS

High Accuracy Broadband Measurement of Anisotropic Dielectric Constant Using a Shielded Planar Dual Mode Resonator.....	25
<i>James C. Rautio, Brian J. Rautio</i>	
Flanged Coaxial Material Probes: Characterizing Exterior CM Energy .....	30
<i>D. J. Rossouw, H. C. Reader, J. Badenhorst</i>	
Stochastic Modeling of Coaxial-Connector Repeatability Errors.....	36
<i>Arkadiusz Lewandowski, Dylan Williams</i>	

## C: MEASUREMENT VERIFICATION I

Metrological Definitions of Verification Methods and Techniques in Microwave Measurements .....	40
<i>Yeou-Song Lee</i>	
Use of Electronic Calibration Units for Vector-Network-Analyzer Verification .....	48
<i>Dylan Williams, Arkadiusz Lewandowski, Denis LeGolvan, Ron Ginley, Chih-Ming Wang, Jolene Splett</i>	
Analyses of VNA Noise Floor.....	56
<i>L. Xinneng, H. Hui</i>	
Verifying Transmission Phase Measurements at Millimeter Wavelengths Using Beadless Air Lines .....	63
<i>Masahiro Horibe, Nick M. Ridder</i>	
Analysis of an RF Power Amplifier for Envelope Tracking based on Load-pull Data .....	70
<i>Marius Ubostad, Morten Olavsraten</i>	
Generalized Method for Broadband Measurement of Extreme Impedances .....	74
<i>M. Randus, K. Hoffmann</i>	
An Online Tool For Transforming Between Different S-Parameter Formats.....	78
<i>M. J. Salter</i>	
An Introduction to Coaxial RF Probing Solutions for Mass-ProductionTests .....	85
<i>Matthias Zapatka, Ralf Ziser</i>	

## D: MEASUREMENT VERIFICATION II

Assessing the Performance of Uncertainty Calculations by Simulation.....	91
<i>B. D. Hall</i>	
Applying Normalized Error Ratio in the Vector Measurement Quantities.....	95
<i>Yeou-Song Lee</i>	
Duty Cycle Dependent Pulsed IV Simulation and Thermal Time Constant Model Fitting for LDMOS Transistors.....	101
<i>Sivalingam Somasundaram Meena, Charles Baylis, Lawrence Dunleavy, Marvin Marbell</i>	

## **E: NONLINEAR AND HIGH-POWER METHODS AND TECHNIQUES**

<b>S-functions Extracted from Narrow-band Modulated Large-signal Network Analyzer Measurements .....</b>	105
<i>Maciej Myslinski, Frans Verheyen, Marc Vanden Bossche, Dominique Schreurs</i>	
<b>Improved Mathematical Model for the Investigation of Deep Traps Into Semiconductor Devices: Application to Metamorphic HEMT .....</b>	113
<i>M. Jaafar, C. Aupetit-Berthelemy, T. Cluzeau, J. P. Teyssier</i>	
<b>Additive Phase Noise Measurements of AlGaN/GaN HEMTs Using a Large Signal Network Analyzer and a Tunable Monochromatic Light Source.....</b>	119
<i>Inwon Suh, Patrick Roblin, Youngseo Ko, Chieh-Kai Yang, Andrew Malonis, Aaron Arehart, Steven Ringel, Christiane Poblenz, Yi Pei, James Speck, Umesh Mishra</i>	
<b>Use of a Step-Response Approximation for Thermal Transient Modeling in Power MOSFETs.....</b>	124
<i>Charles Baylis, Joseph Perry, Matthew Moldovan, Robert J. Marks II, Lawrence Dunleavy</i>	
<b>Author Index</b>	